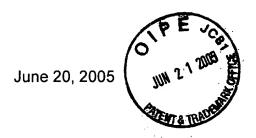
cox

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TRANSMITTAL FORM  (to sused for all correspondence after initial filing)  The number of Pages in This Submission		Application Number		09/854,905	
		Filing Date		May 15, 2001	
		First Named Inventor		MOORE, Brian	
		Art Unit	rt Unit 2829		
		Examiner Name		NGUYEN, Jimmy	
		Attorney Docket Number		11157-23/R	
	5NO. 0		1		
Fee Transmittal Form Drawing(s		SURES (check all that apply)  After Allowance Communication to TC			
	_			Appeal Communication to Board	
Fee Attached	Licensing-	-related Papers		of Appeals and Interferences	
Amendment / Reply	Petition			Appeal Communication to TC (Appeal Notice, Brief, Reply Brief)	
After Final	Petition to Convert to a Provisional Application			Proprietary Information	
Affidavits/declaration(s)	Power of Attorney, Revocation Change of Correspondence Address			Status Letter	
Extension of Time Request	Terminal Disclaimer				nclosure(s) lentify below):
	Request for Refund			Request For Certificate of Correction	
Express Abandonment Request	CD, Number of CD(s)			Certificate of Correction Return Receipt Postcard	
☐ Information Disclosure Statement	☐ Landscape Table on CD			return rece	ipt i ostoard
Certified Copy of Priority Document(s)	Remarks				Certificate
Reply to Missing Parts/		JUN 2 4 2005			
Incomplete Application  Reply to Missing Parts			of Correction		
under 37 CFR1.52 or 1.53	01 0				Of Coffeetion
SIGN	ATURE OF	APPLICANT, ATTOR	RNEY, OF	RAGENT	
Firm	Bereskin & Parr				
Signature	Lylu				
Printed Name	Tony R. Orsi				
Date	June 20, 2005		Reg. No.	55,831	
	CERTIFICA	TE OF TRANSMISS	ION/MAII	LING	
I hereby certify that this correspondence Service with sufficient postage as first Alexandria, VA 22313-1450 on the date	it class mail i	in an envelope addres			
Signature					
Typed or printed name				Date	Γ

# Bereskin & Parr



Tony R. Orsi B.A.Sc. (Elec. Eng.), M.A.Sc. (Biomed. Eng.) 416 957 1603 torsi@bereskinparr.com

Your Reference: 6,759,863 Our Reference: 11157-23/R

REQUEST FOR CERTIFICATE OF CORRECTION UNDER 35 U.S.C. 255 AND 37 C.F.R. 1.323

Commissioner for Patents P.O. Box 1450 Alexandra, Virginia U.S.A. 22313

Attn: Certificate of Correction Branch

Dear Sir:

Re: United States Patent Application No. 09/854,905

Registration No. 6,759,863

For: WIRELESS RADIO FREQUENCY TECHNIQUE DESIGN AND METHOD

FOR TESTING OF INTEGRATED CIRCUITS AND WAFERS

Issued: July 6, 2004 Filed: May 15, 2001

Applicant: MOORE, Brian. Class/Subclass: 324/765 Examiner: NGUYEN, Jimmy

In accordance with the provisions of 35 U.S.C. 255 and 37 C.F.R. 1.322, please find attached a Certificate of Correction form. Since the errors were made by the U.S. Patent Office, the Applicant submits that the fee set forth in 37 CRF 1.20(a) is not required.

The Applicant respectfully submits that the corrections are of a clerical nature and do not constitute new matter or require examination. In particular, the certificate requests that:

- 1) In the Background of The Invention, column 1, line 20, the word –any- be changed to –and-, so that the sentence reads "For quality assurance purposes and for evaluating the manufacturing"
- 2) In the Background of The Invention, column 1, line 31, the punctuation -,- be inserted after the word process, so that the sentence reads "Due to imperfections in the manufacturing process, a certain amount of the ICs will be defective."
- 3) In the Background of The Invention, column 1, line 37, the word manufactures- be changed to –manufacturers-, so that the line reads "This is an investment on the part of the manufacturers that could be"
- 4) In the Background of The Invention, column 1, line 57, the punctuation -.- be deleted after the word defective, so that the sentence reads "The results of these tests may disclose problems in the overall manufacturing process that extend to all the ICs which are fabricated, meanwhile operational tests of the ICs themselves may distinguish individual defective ICs that can then be marked for disposal after dicing."
- 5) In the Background of The Invention, column 2, line 31, the number -6,16,607-be changed to -6,166,607-, so that the sentence reads "Schoellkopf (U.S. Pat. No. 6,166,607) discloses a test method that uses ring oscillators, oscillating at discrete frequencies, as test circuits."
- 6) In the Background of The Invention, column 2, line 44, the punctuation -.- be inserted after the word circuit, so that the sentence reads "However, Schoellkopf requires external probes for powering the test circuit. Furthermore"
- 7) In the Background of The Invention, column 2, line 57, the punctuation -,- be inserted after the word -Consequently-, so that the line reads "Consequently, the IC test method should include characterization"
- 8) In the Summary of The Invention, column 2, line 67, the punctuation -.- be inserted after the word -wafer-, so that the sentence reads "The present invention comprises a test circuit for testing an integrated circuit on a wafer. The"
- 9) In the Summary of The Invention, column 3, line 12, the word –unit- be changed to –circuit-, so that the line reads "The test circuit, when activated by the test unit,"
- 10) In the Summary of The Invention, column 3, line 37, the punctuation -.- be inserted after the word circuit, so that the sentence reads "The test circuit may be formed on the wafer with at least two metallization layers of the integrated circuit."
- 11) In the Summary of The Invention, column 3, line 38, the word –alternatively- be changed to –Alternatively-, so that the sentence reads "Alternatively, the test circuit

may be formed on the wafer with at least one metallization layer and one polysilicon layer of the integrated circuit."

- 12) In the Summary of The Invention, column 3, line 48, the punctuation -.- be inserted after the word –tested-, so that the sentence reads "The analyzing circuit calculates a value of the parameter being tested."
- 13) In the Summary of The Invention, column 3, line 49, the word —or- be changed to —of-, so that the sentence reads "The analyzing circuit may also calculate a ratio of the values of the parameters being tested."
- 14) In the Summary of The Invention, column 4, line 3, the word –last- be changed to –test-, so that the sentence reads "transmission of the test result signal to the test unit."
- 15) In the Summary of The Invention, column 4, line 7, the word -a- be inserted after the word -be-, so that the sentence reads "There may be a plurality of test circuits that are placed on the wafer."
- 16) In the Summary of The Invention, column 4, line 16, the word –water- be changed to –wafer-, so that the sentence reads "a test circuit formed on the wafer with the integrated circuit."
- 17) In the Summary of The Invention, column 4, line 24, the punctuation -;- be inserted after the word circuit, so that the sentence reads "(a) activating the test circuit; "
- 18) In the Summary of The Invention, column 4, line 28, the punctuation -,- be changed to -;-, so that the sentence reads "(c) producing a test result signal in response to each sub-circuit selected by the control circuit; and,"
- 19) In the Summary of The Invention, column 4, line 30, the punctuation -.- be inserted after the word —oscillation-, so that the sentence reads "(d) analyzing the test result signal to determine the frequency of oscillation."
- 20) In the Summary of The Invention, column 4, line 34, the word –fur- be changed to –for-, so that the sentence reads "Alternatively, the method may consist of calculating a ratio of values for the parameter being tested."
- 21) In the Summary of The Invention, column 4, line 37, the punctuation -:- be inserted after the word —of-, so that the sentence reads "The method further comprises effecting step (b) according to the steps of:"
- 22) In the Summary of The Invention, column 4, line 66, the punctuation -,- be inserted after the word —description-, so that the sentence reads "Further objects and advantages of the invention will appear from the following description, taken together with the accompanying drawings."

- 23) In the Brief Description of the Drawings, column 6, line 7, the word -is- be inserted after the number -FIG. 30b-, so that the line reads "FIG. 30b is a spectrum of a simulation result obtained from"
- 24) In the Detailed Description of The Invention, column 6, line 27, the punctuation --- be inserted after the word below, so that the sentence reads "as will be described in greater detail below."
- 25) In the Detailed Description of The Invention, column 6, line 34, the punctuation -.- be inserted after the word tested, so that the sentence reads "whos parameters are to be tested."
- 26) In the Detailed Description of The Invention, column 7, line 11, the word –Testbe changed to –test-, so that the sentence reads "The filtered test result signal 34' is then amplified by the amplifier 40."
- 27) In the Detailed Description of The Invention, column 7, line 13, the word –it- be changed to –is-, so that the line reads "signal 34" is then sent to the"
- 28) In the Detailed Description of The Invention, column 7, line 14, the word –to- be deleted, so that the line reads "phase lock loop 42 which is used to lock onto the"
- 29) In the Detailed Description of The Invention, column 7, line 14, the words phase lock loop- be changed to –phase-locked loop-, so that the sentence reads "then sent to the phase-locked loop 42"
- 30) In the Detailed Description of The Invention, column 7, line 24, the word calculate- be changed to –calculated-, so that the sentence reads "Alternatively, instead of a calculated parameter value,"
- 31) In the Detailed Description of The Invention, column 7, line 37, the word Implemented- be changed to –implemented-, so that the line reads "logic means 46 may be implemented by the same logic"
- 32) In the Detailed Description of The Invention, column 7, line 44, the word –teatbe changed to –test-, so that the line reads "implement the test circuit 14 will also affect the frequency"
- 33) In the Detailed Description of The Invention, column 7, line 59, the word water- be changed to –wafer-, so that the line reads "signal 32 to the area of the wafer 16 where the test circuit 14,"
- 34) In the Detailed Description of The Invention, column 8, line 30, the punctuation -.- be inserted after the word results, so that the sentence reads "they receive and evaluate the test results."

- 35) In the Detailed Description of The Invention, column 8, line 35, the punctuation -,- be inserted after the number 56, so that the line reads "energy storage element 56, a ring oscillator"
- 36) In the Detailed Description of The Invention, column 8, line 39, the word –untilbe changed to –unit-, so that the line reads "transmits the test result signal 34 back to the test unit 12."
- 37) In the Detailed Description of The Invention, column 9, line 18, the word –teatbe changed to –test-, so that the sentence reads " transmitted from the test unit 12."
- 38) In the Detailed Description of The Invention, column 9, line 34, the punctuation -.- be inserted after the word VUR2, so that the sentence reads "voltage VUR2. This process is repeated"
- 39) In the Detailed Description of The Invention, column 9, line 37, the word –usebe changed to –used-, so that the sentence reads "VUR3 are used for power by the other parts,"
- 40) In the Detailed Description of The Invention, column 9, line 54, the word –thenbe changed to –than-, so that the line reads "VDD to be regulated to be less than the threshold voltage of"
- 41) In the Detailed Description of The Invention, column 9, line 60, the word Capacitor- be changed to -capacitor-, so that the line reads "The capacitor CES may store"
- 42) In the Detailed Description of The Invention, column 10, line 12, the equation  $1/(2+n^*t_{inv})$  be changed to  $-1/(2^*n^*t_{inv})$ -, so that the sentence reads " The clock signal 90 therefore has a frequency of  $1/(2^*n^*t_{inv})$  Hz."
- 43) In the Detailed Description of The Invention, column 10, line 15, the word invertors- be changed to –inverters-, so that the sentence reads "a large odd number of inverters such as 101 inverters."
- 44) In the Detailed Description of The Invention, column 10, line 59, the numbers 16 and 17- be changed to –I6 and I7-, so that the sentence reads "two inverters I6 and I7."
- 45) In the Detailed Description of The Invention, column 11, lines 18 and 19, the reference identifiers –16 and 17- be changed to –16 and 17-, so that the sentence reads "functionality (i.e. inverters 16 and 17)"

- 46) In the Detailed Description of The Invention, column 11, line 26, the number 80- be changed to –60-, so that the sentence reads "130 which was used in the sequencer 60."
- 47) In the Detailed Description of The Invention, column 11, line 27, the word clock- be changed to –nck-, so that the sentence reads "The nck signal is the inverse of the clock"
- 48) In the Detailed Description of The Invention, column 11, line 41, the word –usebe changed to –used-, so that the sentence reads "IC 18 may also be used as described further below."
- 49) In the Detailed Description of The Invention, column 11, line 55, the punctuation –.- be inserted after the number -18-, so that the sentence reads "of the IC 18. In this fashion"
- 50) In the Detailed Description of The Invention, column 11, line 56, the punctuation –.- be inserted after –directly-, so that the sentence reads "or directly. Furthermore, various"
- 51) In the Detailed Description of The Invention, column 11, line 56, the word –hebe changed to –be-, so that the sentence reads "Furthermore, various other structures could be substituted"
- 52) In the Detailed Description of The Invention, column 12, line 1, the punctuation –,- be inserted after -S3-, so that the line reads "S1, S2, S3, S4, S5,"
- 53) In the Detailed Description of The Invention, column 12, line 3, the word –sub-circuit- be changed to –sub-circuits-, so that the sentence reads "Most of the sub-circuits that are switched"
- 54) In the Detailed Description of The Invention, column 12, line 62, the word –anbe changed to –on-, so that the sentence reads "comparison is based on dividing equation"
- 55) In the Detailed Description of The Invention, column 13, line 16, the number 164- be changed to –154-, so that the sentence reads "152, 154, 156, 158, 160"
- 56) In the Detailed Description of The Invention, column 13, line 18, the punctuation –,- be inserted after -T2-, so that the sentence reads "gates T2, T3, T6, TN2, TN3 and TN6"
- 57) In the Detailed Description of The Invention, column 13, line 43, the number 116- be changed to –115-, so that the sentence reads "inverters 114, 115 and 116"

- 58) In the Detailed Description of The Invention, column 13, line 44, the word –antibe changed to –and-, so that the sentence reads "sub-circuits 152 and 162 at the"
- 59) In the Detailed Description of The Invention, column 13, line 50, the number 160- be changed to –150-, so that the sentence reads "to be attached to the base ring oscillator 150 when their control signal"
- 60) In the Detailed Description of The Invention, column 15, line 41, the word –farbe changed to –for-, so that the sentence reads "calculating the ratio for the oscillation"
- 61) In the Detailed Description of The Invention, column 16, line 5, the equation 1/(k\*R1\*c3)Hz- be changed to –1/(k\*R1\*C3)Hz-, so that the sentence reads "the variable ring oscillator 62 is 1/(k\*R1\*C3) Hz"
- 62) In the Detailed Description of The Invention, column 16, line 15, the punctuation –.- be inserted after the 150, so that the sentence reads "the base ring oscillator 150. The variable"
- 63) In the Detailed Description of The Invention, column 16, line 35, the equation  $f_{osc2} = 1/(k*((R1+R2)+CL4)))$  be changed to  $f_{osc2} = 1/(k*((R1+R2)*CL4)))$ , so that the equation reads " $f_{osc2} = 1/(k*((R1+R2)*CL4)))$ "
- 64) In the Detailed Description of The Invention, column 16, line 38, the equation  $f_{osc1}/f_{osc2}$ =((R1+R2)(R1)+(CL4/CL3)- be changed to  $f_{osc1}/f_{osc2}$ =((R1+R2)(R1)\*(CL4/CL3))-, so that the equation reads " $f_{osc1}/f_{osc2}$ =((R1+R2)(R1)\*(CL4/CL3))"
- 65) In the Detailed Description of The Invention, column 16, line 41, the word –farebe changed to –fact-, so that the sentence reads "This ratio can be calculated given the fact that"
- 66) In the Detailed Description of The Invention, column 16, line 45, the equation  $f_{osc1}/f_{osc2}$ )- be changed to – $(f_{osc1}/f_{osc2})$ -, so that the sentence reads "oscillation frequencies ( $f_{osc1}/f_{osc2}$ ) should be equal"
- 67) In the Detailed Description of The Invention, column 16, line 50, the word enable- be changed to –enabled-, so that the sentence reads "that are enabled during test state"
- 68) In the Detailed Description of The Invention, column 16, line 59, the equation  $1/(T_{inv})Hz$  be changed to  $-1/(7^*T_{inv})Hz$ -, so that the sentence reads "oscillator 62 will be  $1/(7^*T_{inv})Hz$  where"
- 69) In the Detailed Description of The Invention, column 17, line 6, the word bases- be changed to –based-, so that the sentence reads "would have been expected based on simulations"

- 70) In the Detailed Description of The Invention, column 18, line 63, the number FIG. 25- be changed to –FIG. 28-, so that the sentence reads "as previously described for the embodiment shown in FIG. 28."
- 71) In the Detailed Description of The Invention, column 19, line 2, the word metalization- be changed to –metallization-, so that the sentence reads "Alternatively, more metallization layers could be"
- 72) In the Detailed Description of The Invention, column 19, line 4, the word metalization- be changed to –metallization-, so that the sentence reads "can be fabricated with two metallization layers"
- 73) In the Detailed Description of The Invention, column 19, line 11, the word –sub-circuit- be changed to –sub-circuits-, so that the sentence reads "most of the sub-circuits within the IC"
- 74) In the Detailed Description of The Invention, column 19, line 22, the word –a-, be inserted so that the sentence reads "which is a widely used IC"
- 75) In the Detailed Description of The Invention, column 19, line 27, the initials –IF-be changed to –fF-, so that the sentence reads "values of 200 fF and 400 fF and two resistors"
- 76) In the Detailed Description of The Invention, column 19, line 36, the punctuation –,- be inserted after the word capacitance, so that the sentence reads "for capacitance, there was a distinct difference"
- 77) In the Detailed Description of The Invention, column 19, line 43, the punctuation –,- be inserted after the words –test- and –cases-, and the word –this- be changed to these- so that the sentence reads "parameter test, in these cases, there was also two discernible"
- 78) In the Detailed Description of The Invention, column 19, line 52, a space before the word -as- be inserted, so that the sentence reads ") as well as different IC technologies"
- 79) In the Detailed Description of The Invention, column 20, line 10, the word VISI-, be changed to -VLSI-, so that the sentence reads "exemplary purposes with standard VLSI CAD tools"

80) In the Detailed Description of The Invention, column 20, line 13, the number - 60-, be changed to -50-, so that the sentence reads "without the antenna, was approximately 150 by 50 micrometers and comprised"

Respectfully submitted,

Bereskin & Parr

Tony R. Orsi

Registration No. 55,831

/cec Encl.

PATENT NO: U.S. 6,759,863 B2

Page <u>1</u> of <u>7</u>

DATED : July 6, 2004

INVENTOR(S): Brian Moore

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

In the Background of The Invention, column 1, line 20, the word –any- has been changed to –and-, so that the sentence reads "For quality assurance purposes and for evaluating the manufacturing"

In the Background of The Invention, column 1, line 31, the punctuation -,- has been inserted after the word process, so that the sentence reads "Due to imperfections in the manufacturing process, a certain amount of the ICs will be defective."

In the Background of The Invention, column 1, line 37, the word —manufactures- has been changed to —manufacturers-, so that the line reads "This is an investment on the part of the manufacturers that could be"

In the Background of The Invention, column 1, line 57, the punctuation -.- has been deleted after the word defective, so that the sentence reads "The results of these tests may disclose problems in the overall manufacturing process that extend to all the ICs which are fabricated, meanwhile operational tests of the ICs themselves may distinguish individual defective ICs that can then be marked for disposal after dicing."

In the Background of The Invention, column 2, line 31, the number -6,16,607- has been changed to -6,166,607, so that the sentence reads "Schoellkopf (U.S. Pat. No. 6,166,607) discloses a test method that uses ring oscillators, oscillating at discrete frequencies, as test circuits."

In the Background of The Invention, column 2, line 44, the punctuation -.- has been inserted after the word circuit, so that the sentence reads "However, Schoellkopf requires external probes for powering the test circuit. Furthermore"

In the Background of The Invention, column 2, line 57, the punctuation -,- has been inserted after the word - Consequently-, so that the line reads "Consequently, the IC test method should include characterization"

In the Summary of The Invention, column 2, line 67, the punctuation -.- has been inserted after the word -wafer-, so that the sentence reads "The present invention comprises a test circuit for testing an integrated circuit on a wafer. The"

In the Summary of The Invention, column 3, line 12, the word –unit- has been changed to –circuit-, so that the line reads "The test circuit, when activated by the test unit,"

In the Summary of The Invention, column 3, line 37, the punctuation -.- has been inserted after the word circuit, so that the sentence reads "The test circuit may be formed on the wafer with at least two metallization layers of the integrated circuit."

MAILING ADDRESS OF SENDER (Please do not use customer number below):

Bereskin & Parr Box 401, 40 King Street West Toronto, Ontario, M5H 3Y2, Canada

PATENT NO: U.S. 6,759,863 B2

Page 2 of 7

DATED : July 6, 2004 INVENTOR(S) : Brian Moore

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In the Summary of The Invention, column 3, line 38, the word –alternatively- has been changed to –Alternatively, so that the sentence reads "Alternatively, the test circuit may be formed on the wafer with at least one metallization layer and one polysilicon layer of the integrated circuit."

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In the Summary of The Invention, column 3, line 49, the word –or- has been changed to –of-, so that the sentence reads "The analyzing circuit may also calculate a ratio of the values of the parameters being tested."

In the Summary of The Invention, column 4, line 3, the word –last- has been changed to –test-, so that the sentence reads "transmission of the test result signal to the test unit."

In the Summary of The Invention, column 4, line 7, the word -a- has been inserted after the word -be-, so that the sentence reads "There may be a plurality of test circuits that are placed on the wafer."

In the Summary of The Invention, column 4, line 16, the word –water- has been changed to –wafer-, so that the sentence reads "a test circuit formed on the wafer with the integrated circuit,"

In the Summary of The Invention, column 4, line 24, the punctuation -;- has been inserted after the word circuit, so that the sentence reads "(a) activating the test circuit; "

In the Summary of The Invention, column 4, line 28, the punctuation -,- has been changed to -;-, so that the sentence reads "(c) producing a test result signal in response to each sub-circuit selected by the control circuit; and,"

In the Summary of The Invention, column 4, line 30, the punctuation -.- has been inserted after the word -oscillation-, so that the sentence reads "(d) analyzing the test result signal to determine the frequency of oscillation."

In the Summary of The Invention, column 4, line 34, the word –fur- has been changed to –for-, so that the sentence reads "Alternatively, the method may consist of calculating a ratio of values for the parameter being tested."

In the Summary of The Invention, column 4, line 37, the punctuation -:- has been inserted after the word -of-, so that the sentence reads "The method further comprises effecting step (b) according to the steps of:"

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PATENT NO: U.S. 6,759,863 B2

Page 3 of 7

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In the Detailed Description of The Invention, column 7, line 59, the word –water- has been changed to –wafer-, so that the line reads "signal 32 to the area of the wafer 16 where the test circuit 14,"

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PATENT NO: U.S. 6,759,863 B2

Page <u>4</u> of <u>7</u>

DATED : July 6, 2004 INVENTOR(S) : Brian Moore

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

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In the Detailed Description of The Invention, column 9, line 18, the word –teat- has been changed to –test-, so that the sentence reads "transmitted from the test unit 12."

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In the Detailed Description of The Invention, column 9, line 37, the word –use- has been changed to –used-, so that the sentence reads "VUR3 are used for power by the other parts,"

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In the Detailed Description of The Invention, column 9, line 60, the word -Capacitor- has been changed to -capacitor-, so that the line reads "The capacitor CES may store"

In the Detailed Description of The Invention, column 10, line 12, the equation  $-1/(2+n^*t_{inv})$ - has been changed to  $-1/(2^*n^*t_{inv})$ -, so that the sentence reads " The clock signal 90 therefore has a frequency of  $1/(2^*n^*t_{inv})$  Hz."

In the Detailed Description of The Invention, column 10, line 15, the word –invertors- has been changed to –inverters-, so that the sentence reads "a large odd number of inverters such as 101 inverters."

In the Detailed Description of The Invention, column 10, line 59, the numbers –16 and 17- has been changed to –16 and 17-, so that the sentence reads "two inverters I6 and I7."

In the Detailed Description of The Invention, column 11, lines 18 and 19, the reference identifiers –16 and 17- has been changed to –16 and 17-, so that the sentence reads "functionality (i.e. inverters 16 and 17)"

In the Detailed Description of The Invention, column 11, line 26, the number –80- has been changed to –60-, so that the sentence reads "130 which was used in the sequencer 60."

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PATENT NO: U.S. 6,759,863 B2

Page <u>5</u> of <u>7</u>

DATED : July 6, 2004 INVENTOR(S) : Brian Moore

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

In the Detailed Description of The Invention, column 11, line 27, the word –clock- has been changed to –nck-, so that the sentence reads "The nck signal is the inverse of the clock"

In the Detailed Description of The Invention, column 11, line 41, the word –use- has been changed to –used-, so that the sentence reads "IC 18 may also be used as described further below."

In the Detailed Description of The Invention, column 11, line 55, the punctuation –.- has been inserted after the number -18-, so that the sentence reads "of the IC 18. In this fashion"

In the Detailed Description of The Invention, column 11, line 56, the punctuation -.- has been inserted after -directly-, so that the sentence reads "or directly. Furthermore, various"

In the Detailed Description of The Invention, column 11, line 56, the word –he- has been changed to –be-, so that the sentence reads "Furthermore, various other structures could be substituted"

In the Detailed Description of The Invention, column 12, line 1, the punctuation –,- has been inserted after -S3-, so that the line reads "S1, S2, S3, S4, S5,"

In the Detailed Description of The Invention, column 12, line 3, the word –sub-circuit- has been changed to –sub-circuits-, so that the sentence reads "Most of the sub-circuits that are switched"

In the Detailed Description of The Invention, column 12, line 62, the word –an- has been changed to –on-, so that the sentence reads "comparison is based on dividing equation"

In the Detailed Description of The Invention, column 13, line 16, the number –164- has been changed to –154-, so that the sentence reads "152, 154, 156, 158, 160"

In the Detailed Description of The Invention, column 13, line 18, the punctuation -,- has been inserted after -T2-, so that the sentence reads "gates T2, T3, T6, TN2, TN3 and TN6"

In the Detailed Description of The Invention, column 13, line 43, the number –I16- has been changed to –I15-, so that the sentence reads "inverters I14, I15 and I16"

In the Detailed Description of The Invention, column 13, line 44, the word -anti- has been changed to -and-, so that the sentence reads "sub-circuits 152 and 162 at the"

In the Detailed Description of The Invention, column 13, line 50, the number –160- has been changed to –150-, so that the sentence reads "to be attached to the base ring oscillator 150 when their control signal"

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DATED : July 6, 2004 INVENTOR(S) : Brian Moore

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

In the Detailed Description of The Invention, column 15, line 41, the word –far- has been changed to –for-, so that the sentence reads "calculating the ratio for the oscillation"

In the Detailed Description of The Invention, column 16, line 5, the equation -1/(k\*R1\*c3)Hz- has been changed to -1/(k\*R1\*C3)Hz-, so that the sentence reads "the variable ring oscillator 62 is 1/(k\*R1\*C3) Hz"

In the Detailed Description of The Invention, column 16, line 15, the punctuation —.- has been inserted after the 150, so that the sentence reads "the base ring oscillator 150. The variable"

In the Detailed Description of The Invention, column 16, line 35, the equation  $-f_{osc2} = 1/(k^*((R1+R2)+CL4)))$  has been changed to  $-f_{osc2} = 1/(k^*((R1+R2)*CL4)))$ , so that the equation reads " $f_{osc2} = 1/(k^*((R1+R2)*CL4)))$ "

In the Detailed Description of The Invention, column 16, line 38, the equation  $-f_{osc1}/f_{osc2}=((R1+R2)(R1)+(CL4/CL3)-f_{osc2})$  has been changed to  $-f_{osc1}/f_{osc2}=((R1+R2)(R1)+(CL4/CL3))-f_{osc2}$  =((R1+R2)(R1)+(CL4/CL3))"

In the Detailed Description of The Invention, column 16, line 41, the word –fare- has been changed to –fact-, so that the sentence reads "This ratio can be calculated given the fact that"

In the Detailed Description of The Invention, column 16, line 45, the equation  $-f_{osc1}/f_{osc2}$ )- has been changed to  $-(f_{osc1}/f_{osc2})$ -, so that the sentence reads "oscillation frequencies  $(f_{osc1}/f_{osc2})$  should be equal"

In the Detailed Description of The Invention, column 16, line 50, the word –enable- has been changed to –enabled, so that the sentence reads "that are enabled during test state"

In the Detailed Description of The Invention, column 16, line 59, the equation  $-1/(T_{inv})Hz$ - has been changed to  $-1/(7^*T_{inv})Hz$ -, so that the sentence reads "oscillator 62 will be  $1/(7^*T_{inv})Hz$  where"

In the Detailed Description of The Invention, column 17, line 6, the word –bases- has been changed to –based-, so that the sentence reads "would have been expected based on simulations"

In the Detailed Description of The Invention, column 18, line 63, the number –FIG. 25- has been changed to –FIG. 28-, so that the sentence reads "as previously described for the embodiment shown in FIG. 28."

In the Detailed Description of The Invention, column 19, line 2, the word –metalization- has been changed to –metallization-, so that the sentence reads "Alternatively, more metallization layers could be"

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DATED : July 6, 2004

INVENTOR(S): Brian Moore

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

In the Detailed Description of The Invention, column 19, line 4, the word –metalization- has been changed to –metallization-, so that the sentence reads "can be fabricated with two metallization layers"

In the Detailed Description of The Invention, column 19, line 11, the word –sub-circuit- has been changed to –sub-circuits-, so that the sentence reads "most of the sub-circuits within the IC"

In the Detailed Description of The Invention, column 19, line 22, the word -a-, has been inserted so that the sentence reads "which is a widely used IC"

In the Detailed Description of The Invention, column 19, line 27, the initials –IF- has been changed to –fF-, so that the sentence reads "values of 200 fF and 400 fF and two resistors"

In the Detailed Description of The Invention, column 19, line 36, the punctuation -,- has been inserted after the word capacitance, so that the sentence reads "for capacitance, there was a distinct difference"

In the Detailed Description of The Invention, column 19, line 43, the punctuation -,- has been inserted after the words -test- and -cases-, and the word -this- be changed to -these- so that the sentence reads "parameter test, in these cases, there was also two discernible"

In the Detailed Description of The Invention, column 19, line 52, a space before the word –as- has been inserted, so that the sentence reads ") as well as different IC technologies"

In the Detailed Description of The Invention, column 20, line 10, the word -VISI-, has been changed to -VLSI-, so that the sentence reads "exemplary purposes with standard VLSI CAD tools"

In the Detailed Description of The Invention, column 20, line 13, the number –60-, has been changed to -50-, so that the sentence reads "without the antenna, was approximately 150 by 50 micrometers and comprised"

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